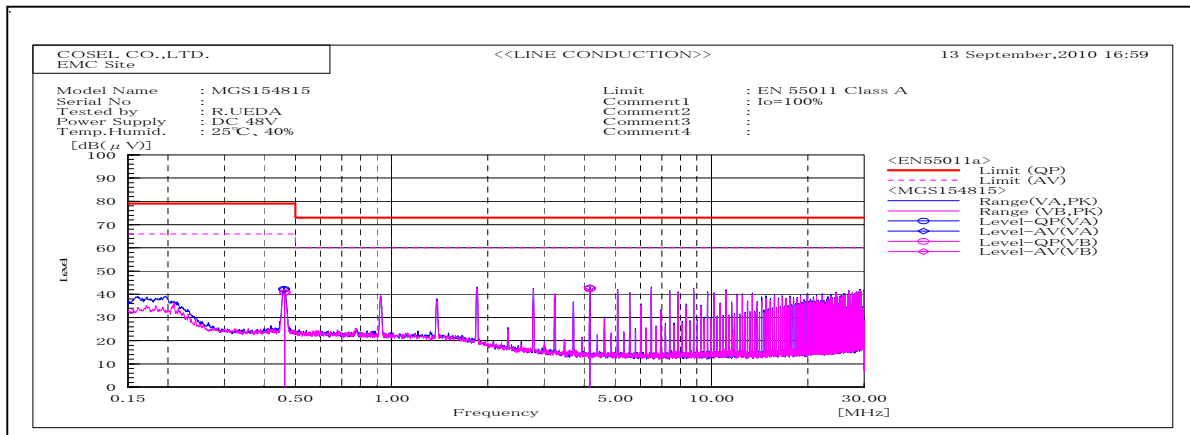
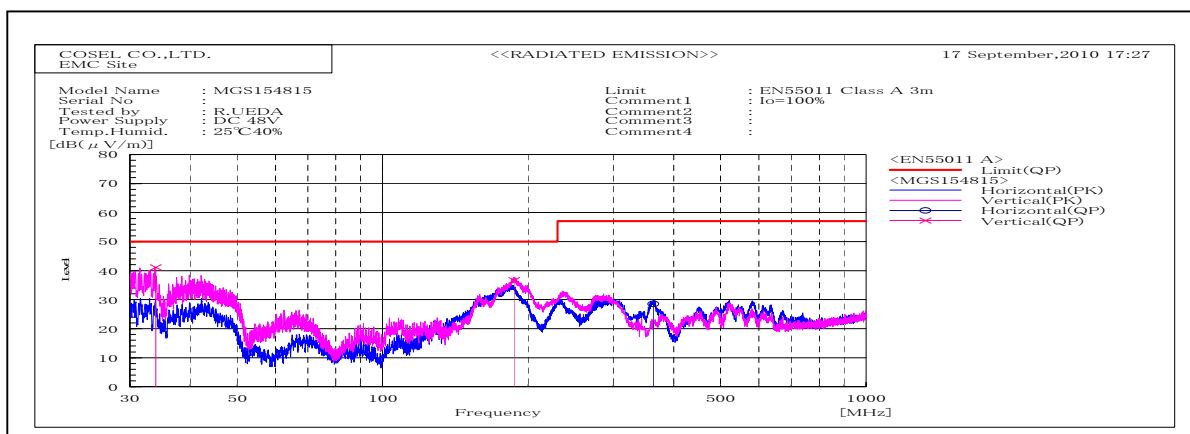


DATA SHEET		Date	21-Sep-10
Model	MGS154815	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	R.Ueda



Frequency MHz	Harm	Line Phase	Reading dB(μV)		Factor dB	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.46177		VA	32.1	32	10.1	42.2	42.1	79	66	36.8	23.9	Pass	
0.46416		VB	30.8	30.7	10	40.8	40.7	79	66	38.2	25.3	Pass	
4.16544		VB	32.1	32.4	10.3	42.4	42.7	73	60	30.6	17.3	Pass	
4.16638		VA	32.2	32.5	10.3	42.5	42.8	73	60	30.5	17.2	Pass	



Frequency MHz	Polarization	Stability	Reading dB(μV)		Space Loss dB	Level dB(mW)		Limit dB(mW)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	AV		QP	AV						
33.95	V	Stable	56.6	-15.5		41.1		50	8.9	Pass	104	9	
187.155	V	Stable	58.8	-22.1		36.7		50	13.3	Pass	134	236	
362.93	H	Stable	44.3	-15.8		28.5		57	28.5	Pass	101	166	

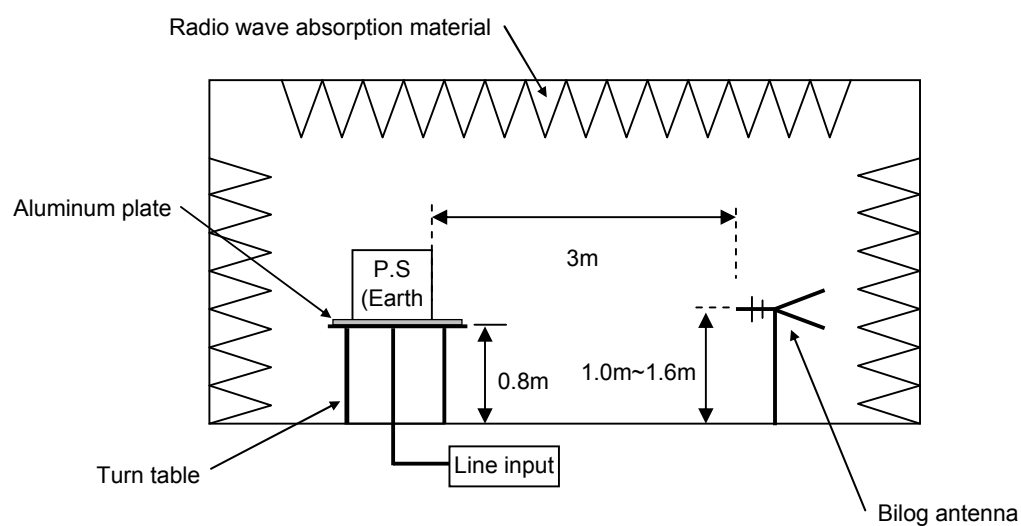
# DATA SHEET

Model	Circuit used for measurement
Test	EMI Line conduction & Radiated emission

## 1. Line conduction



## 2. Radiated emission



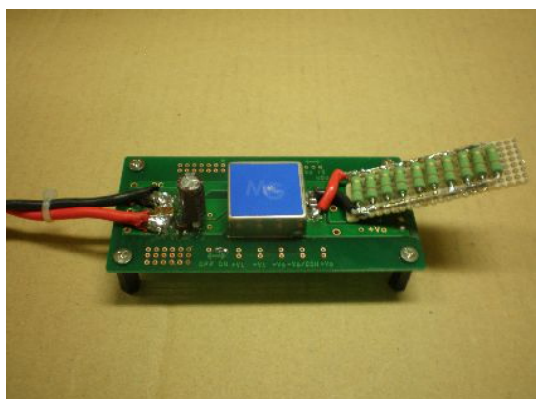


## Conditions

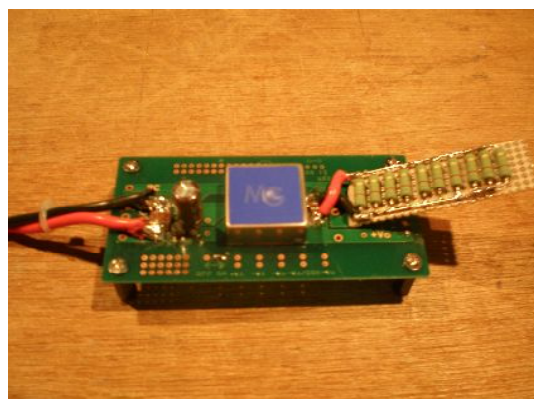
Test : EMI  
Model Name : MGS1548□□/MGW1548□□

○Photographs of Test Set-Up

### LINE CONDUCTION



### RADIATED EMISSION



○Testing circuitry

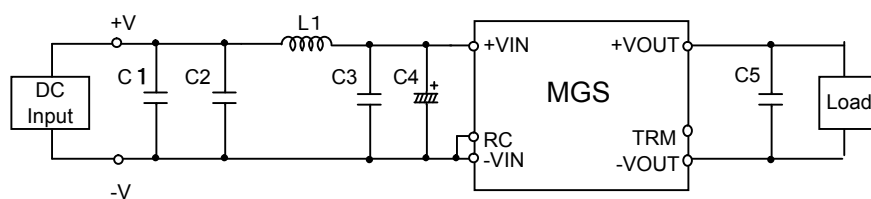


Fig.1 Testing circuitry 1

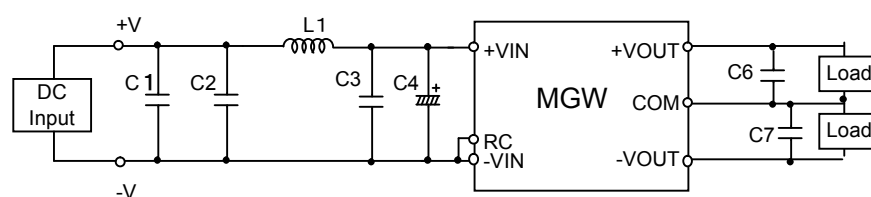


Fig.2 Testing circuitry 2

L1	: 10 $\mu$ H	CI4C-100	(KORIN ELECTRONICS)
C1,C2,C3	: 100V	2.2 $\mu$ F	C4532JB2A225MT (TDK)
C4	: 80V	47 $\mu$ F	LXV80VB47M (NIPPON CHEMI-CON)
C5,C6,C7	: 25V	22 $\mu$ F	CM32X5R226K25A (KYOCERA)